

(12) **INTER PARTES REVIEW CERTIFICATE** (2980th)

United States Patent
Grupp et al.

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(45) **Certificate Issued:** **Jan. 25, 2023**

(54) **METHOD FOR DEPINNING THE FERMI
LEVEL OF A SEMICONDUCTOR AT AN
ELECTRICAL JUNCTION AND DEVICES
INCORPORATING SUCH JUNCTIONS**

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The results of IPR2020-01207; IPR2020-01282 are reflected in this inter partes review certificate under 35 U.S.C. 318(b).

INTER PARTES REVIEW CERTIFICATE
U.S. Patent 10,090,395 K1
Trial No. IPR2020-01207
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AS A RESULT OF THE INTER PARTES
REVIEW PROCEEDING, IT HAS BEEN
DETERMINED THAT:

Claims **11, 12, 14** and **17-28** are found patentable.

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Claims **1-6, 8-9, 15** and **16** are cancelled.

Claim **10** is disclaimed.

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